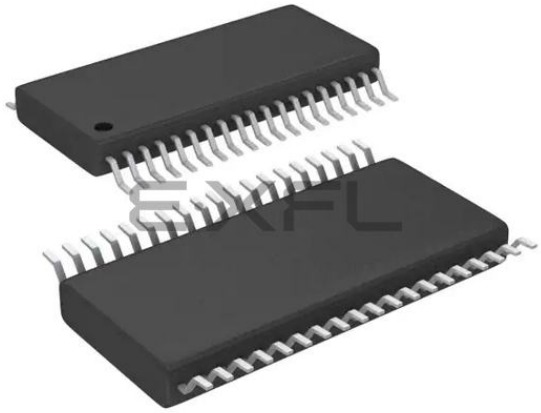
Infineon Technologies - XMC1302T038X0200ABXUMA1 Datasheet



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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	ARM® Cortex®-M0
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I²C, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, I²S, POR, PWM, WDT
Number of I/O	26
Program Memory Size	200KB (200K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 5.5V
Data Converters	A/D 16x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	38-TFSOP (0.173", 4.40mm Width)
Supplier Device Package	PG-TSSOP-38-9
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xmc1302t038x0200abxuma1

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About this Document

This Data Sheet is addressed to embedded hardware and software developers. It provides the reader with detailed descriptions about the ordering designations, available features, electrical and physical characteristics of the XMC1300 series devices.

The document describes the characteristics of a superset of the XMC1300 series devices. For simplicity, the various device types are referred to by the collective term XMC1300 throughout this document.

XMC1000 Family User Documentation

The set of user documentation includes:

- **Reference Manual**
  – decribes the functionality of the superset of devices.
- **Data Sheets**
  – list the complete ordering designations, available features and electrical characteristics of derivative devices.
- **Errata Sheets**
  – list deviations from the specifications given in the related Reference Manual or Data Sheets. Errata Sheets are provided for the superset of devices.

Attention: Please consult all parts of the documentation set to attain consolidated knowledge about your device.

Application related guidance is provided by **Users Guides** and **Application Notes**.

Please refer to **http://www.infineon.com/xmc1000** to get access to the latest versions of those documents.

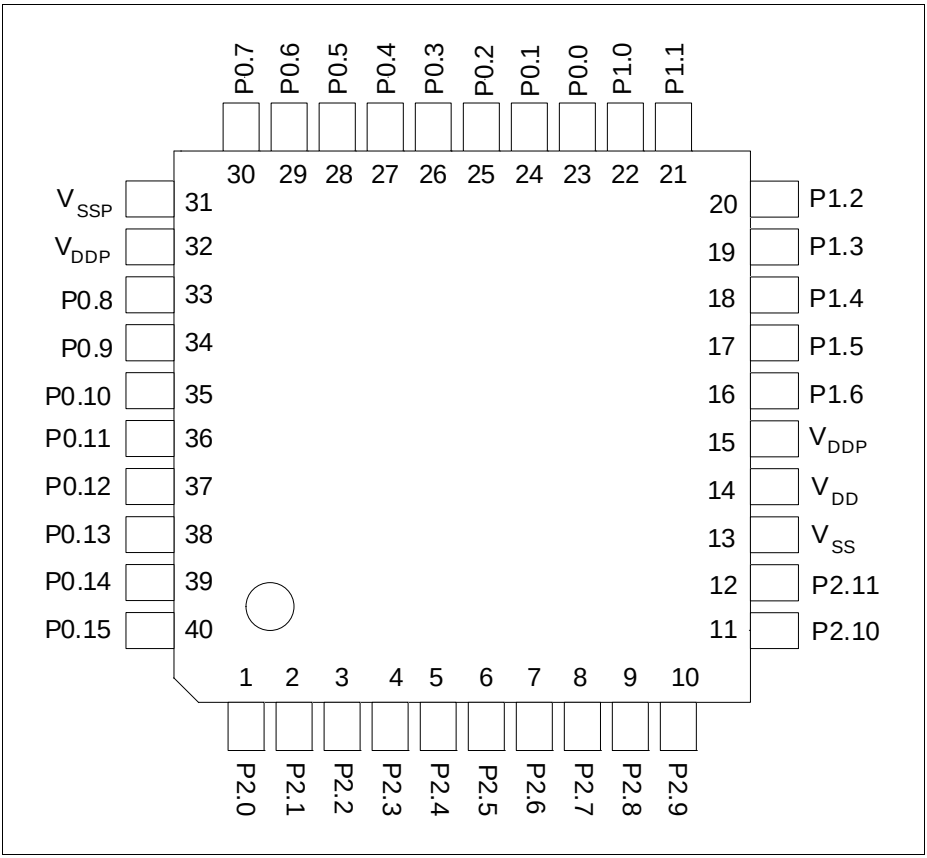


Figure 8 XMC1300 PG-VQFN-40 Pin Configuration (top view)

Table 6 Package Pin Mapping (cont'd)

Function	VQFN 40	TSSOP 38	TSSOP 28	VQFN 24	TSSOP 16	Pad Type	Notes
P0.7	30	24	17	18	10	STD_IN OUT	
P0.8	33	27	18	19	11	STD_IN OUT	
P0.9	34	28	19	20	12	STD_IN OUT	
P0.10	35	29	20	-	-	STD_IN OUT	
P0.11	36	30	-	-	-	STD_IN OUT	
P0.12	37	31	21	21	-	STD_IN OUT	
P0.13	38	32	22	22	-	STD_IN OUT	
P0.14	39	33	23	23	13	STD_IN OUT	
P0.15	40	34	24	24	14	STD_IN OUT	
P1.0	22	16	12	14	-	High Current	
P1.1	21	15	11	13	-	High Current	
P1.2	20	14	10	12	-	High Current	
P1.3	19	13	9	11	-	High Current	
P1.4	18	12	-	-	-	High Current	
P1.5	17	11	-	-	-	High Current	
P1.6	16	-	-	-	-	STD_IN OUT	
P2.0	1	35	25	1	15	STD_IN OUT/AN	

Table 9 Port I/O Functions (cont'd)

Function	Outputs							Inputs									
	ALT1	ALT2	ALT3	ALT4	ALT5	ALT6	ALT7	Input	Input	Input	Input	Input	Input	Input	Input	Input	Input
P0.14	BCCU0.OUT7				CCU80.OUT31	USIC0_CH0.DOUT0	USIC0_CH0.SCLKOUT			POSIF0.IN1B		USIC0_CH0.DX0A	USIC0_CH0.DX1A				
P0.15	BCCU0.OUT8				CCU80.OUT30	USIC0_CH0.DOUT0	USIC0_CH1.MCLKOUT			POSIF0.IN2B		USIC0_CH0.DX0B					
P1.0	BCCU0.OUT0	CCU40.OUT0			CCU80.OUT00	ACMP1.OUT	USIC0_CH0.DOUT0			POSIF0.IN2A		USIC0_CH0.DX0C					
P1.1	VADC0.EMUX00	CCU40.OUT1			CCU80.OUT01	USIC0_CH0.DOUT0	USIC0_CH1.SELO0			POSIF0.IN1A		USIC0_CH0.DX0D	USIC0_CH0.DX1D	USIC0_CH1.DX2E			
P1.2	VADC0.EMUX01	CCU40.OUT2			CCU80.OUT10	ACMP2.OUT	USIC0_CH1.DOUT0			POSIF0.IN0A		USIC0_CH1.DX0B					
P1.3	VADC0.EMUX02	CCU40.OUT3			CCU80.OUT11	USIC0_CH1.SCLKOUT	USIC0_CH1.DOUT0					USIC0_CH1.DX0A	USIC0_CH1.DX1A				
P1.4	VADC0.EMUX10	USIC0_CH1.SCLKOUT			CCU80.OUT20	USIC0_CH0.SELO0	USIC0_CH1.SELO1					USIC0_CH0.DX5E	USIC0_CH1.DX5E				
P1.5	VADC0.EMUX11	USIC0_CH0.DOUT0		BCCU0.OUT1	CCU80.OUT21	USIC0_CH0.SELO1	USIC0_CH1.SELO2					USIC0_CH1.DX5F					
P1.6	VADC0.EMUX12	USIC0_CH1.DOUT0		USIC0_CH0.SCLKOUT	BCCU0.OUT2	USIC0_CH0.SELO2	USIC0_CH1.SELO3			USIC0_CH0.DX5F							
P2.0	ERU0.PDOUT3	CCU40.OUT0	ERU0.GOUT3		CCU80.OUT20	USIC0_CH0.DOUT0	USIC0_CH0.SCLKOUT		VADC0.G0CH5		ERU0.0B0	USIC0_CH0.DX0E	USIC0_CH0.DX1E	USIC0_CH1.DX2F			
P2.1	ERU0.PDOUT2	CCU40.OUT1	ERU0.GOUT2		CCU80.OUT21	USIC0_CH0.DOUT0	USIC0_CH1.SCLKOUT	ACMP2.INP	VADC0.G0CH6		ERU0.1B0	USIC0_CH0.DX0F	USIC0_CH1.DX3A	USIC0_CH1.DX4A			
P2.2								ACMP2.INN	VADC0.G0CH7		ERU0.0B1	USIC0_CH0.DX3A	USIC0_CH0.DX4A	USIC0_CH1.DX5A	ORC0.AIN		
P2.3									VADC0.G1CH5		ERU0.1B1	USIC0_CH0.DX5B	USIC0_CH1.DX3C	USIC0_CH1.DX4C	ORC1.AIN		
P2.4									VADC0.G1CH6		ERU0.0A1	USIC0_CH0.DX3B	USIC0_CH0.DX4B	USIC0_CH1.DX5B	ORC2.AIN		
P2.5									VADC0.G1CH7		ERU0.1A1	USIC0_CH0.DX5D	USIC0_CH1.DX3E	USIC0_CH1.DX4E	ORC3.AIN		

3.1.2 Absolute Maximum Ratings

Stresses above the values listed under “Absolute Maximum Ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions may affect device reliability.

Table 11 Absolute Maximum Rating Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Junction temperature	T_J	SR	-40	–	115	°C	–
Storage temperature	T_{ST}	SR	-40	–	125	°C	–
Voltage on power supply pin with respect to V_{SSP}	V_{DDP}	SR	-0.3	–	6	V	–
Voltage on digital pins with respect to V_{SSP} [1]	V_{IN}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	whichever is lower
Voltage on P2 pins with respect to V_{SSP} [2]	V_{INP2}	SR	-0.3	–	V_{DDP} + 0.3	V	–
Voltage on analog input pins with respect to V_{SSP}	V_{AIN} V_{AREF}	SR	-0.5	–	V_{DDP} + 0.5 or max. 6	V	whichever is lower
Input current on any pin during overload condition	I_{IN}	SR	-10	–	10	mA	–
Absolute maximum sum of all input currents during overload condition	ΣI_{IN}	SR	-50	–	+50	mA	–

1) Excluding port pins P2.[1,2,6,7,8,9,11].

2) Applicable to port pins P2.[1,2,6,7,8,9,11].

3.1.3 Pin Reliability in Overload

When receiving signals from higher voltage devices, low-voltage devices experience overload currents and voltages that go beyond their own IO power supplies specification.

Table 12 defines overload conditions that will not cause any negative reliability impact if all the following conditions are met:

- full operation life-time is not exceeded
- **Operating Conditions** are met for
  - pad supply levels (V_{DDP})
  - temperature

If a pin current is outside of the **Operating Conditions** but within the overload conditions, then the parameters of this pin as stated in the Operating Conditions can no longer be guaranteed. Operation is still possible in most cases but with relaxed parameters.

Note: An overload condition on one or more pins does not require a reset.

Note: A series resistor at the pin to limit the current to the maximum permitted overload current is sufficient to handle failure situations like short to battery.

Table 12 Overload Parameters

Parameter	Symbol		Values			Unit	Note / Test Condition
			Min.	Typ.	Max.		
Input current on any port pin during overload condition	I_{OV}	SR	-5	–	5	mA	
Absolute sum of all input circuit currents during overload condition	I_{OVS}	SR	–	–	25	mA	

Figure 10 shows the path of the input currents during overload via the ESD protection structures. The diodes against V_{DDP} and ground are a simplified representation of these ESD protection structures.

Table 17 ADC Characteristics (Operating Conditions apply)[1)] (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Gain settings	G_{IN} CC	1			–	GNCTRxz.GAINy = 00_B (unity gain)
		3			–	GNCTRxz.GAINy = 01_B (gain g1)
		6			–	GNCTRxz.GAINy = 10_B (gain g2)
		12			–	GNCTRxz.GAINy = 11_B (gain g3)
Sample Time	t_{sample} CC	3	–	–	1 / f_{ADC}	V_{DD} = 5.0 V
		3	–	–	1 / f_{ADC}	V_{DD} = 3.3 V
		30	–	–	1 / f_{ADC}	V_{DD} = 2.0 V
Sigma delta loop hold time	t_{SD_hold} CC	20	–	–	µs	Residual charge stored in an active sigma delta loop remains available
Conversion time in fast compare mode	t_{CF} CC	9			1 / f_{ADC}	2)
Conversion time in 12-bit mode	t_{C12} CC	20			1 / f_{ADC}	2)
Maximum sample rate in 12-bit mode 3)	f_{C12} CC	–	–	f_{ADC} / 42.5	–	1 sample pending
		–	–	f_{ADC} / 62.5	–	2 samples pending
Conversion time in 10-bit mode	t_{C10} CC	18			1 / f_{ADC}	2)
Maximum sample rate in 10-bit mode 3)	f_{C10} CC	–	–	f_{ADC} / 40.5	–	1 sample pending
		–	–	f_{ADC} / 58.5	–	2 samples pending
Conversion time in 8-bit mode	t_{C8} CC	16			1 / f_{ADC}	2)

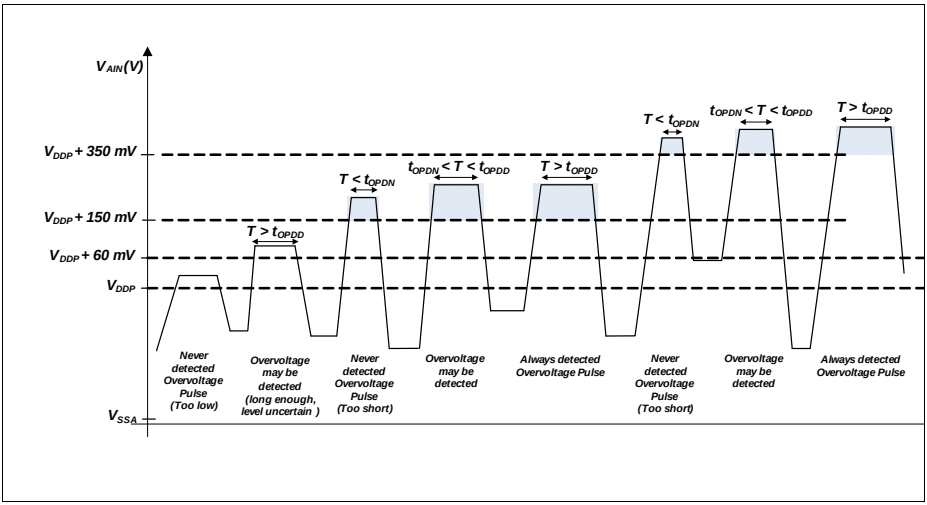


Figure 13 ORC Detection Ranges

3.2.5 Temperature Sensor Characteristics

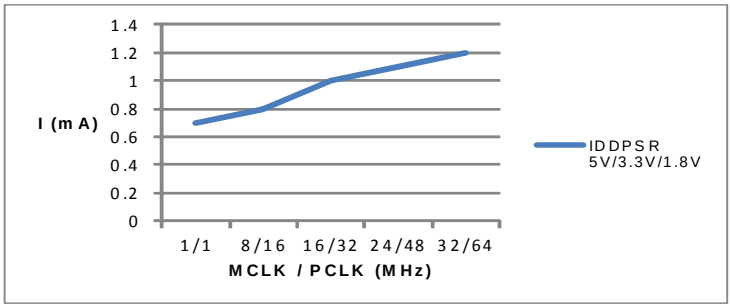
Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 20 Temperature Sensor Characteristics

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Measurement time	t_M CC	–	–	10	ms	
Temperature sensor range	T_{SR} SR	-40	–	115	°C	
Sensor Accuracy[1)]	T_{TSAL} CC	-6	–	6	°C	T_J > 20°C
		-10	–	10	°C	0°C ≤ T_J ≤ 20°C
		–	-/+8	–	°C	T_J < 0°C
Start-up time after enabling	t_{TSSTE} SR	–	–	15	µs	

1) The temperature sensor accuracy is independent of the supply voltage.

Figure 15 shows typical graphs for sleep mode current for V_{DDP} = 5V, V_{DDP} = 3.3V, V_{DDP} = 1.8V across different clock frequencies.



Condition:
1. TA = +25° C

Figure 15 Sleep mode, peripherals clocks disabled, Flash powered down: Supply current I_{DDPSR} over supply voltage V_{DDP} for different clock frequencies

3.2.7 Flash Memory Parameters

Note: These parameters are not subject to production test, but verified by design and/or characterization.

Table 23 Flash Memory Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Erase Time per page / sector	t_{ERASE} CC	6.8	7.1	7.6	ms	
Program time per block	t_{PSER} CC	102	152	204	µs	
Wake-Up time	t_{WU} CC	–	32.2	–	µs	
Read time per word	t_a CC	–	50	–	ns	
Data Retention Time	t_{RET} CC	10	–	–	years	Max. 100 erase / program cycles
Flash Wait States [1]	$N_{WSFLASH}$ CC	0	0	0		f_{MCLK} = 8 MHz
		0	1	1		f_{MCLK} = 16 MHz
		1	1.3	2		f_{MCLK} = 32 MHz
Fixed Flash Wait States configured in bit NVM_NVMCONF.WS	$N_{FWSFLASH}$ SR	0	0	1		NVM_CONFIG1.FIXWS = 1_B, $f_{MCLK} \leq$ 16 MHz
		1	1	1		NVM_CONFIG1.FIXWS = 1_B, 16 MHz < $f_{MCLK} \leq$ 32 MHz
Erase Cycles	N_{ECYC} CC	–	–	$5*10^4$	cycles	Sum of page and sector erase cycles
Total Erase Cycles	N_{TECYC} CC	–	–	$2*10^6$	cycles	

1) Flash wait states are automatically inserted by the Flash module during memory read when needed. Typical values are calculated from the execution of the Dhrystone benchmark program.

3.3 AC Parameters

3.3.1 Testing Waveforms

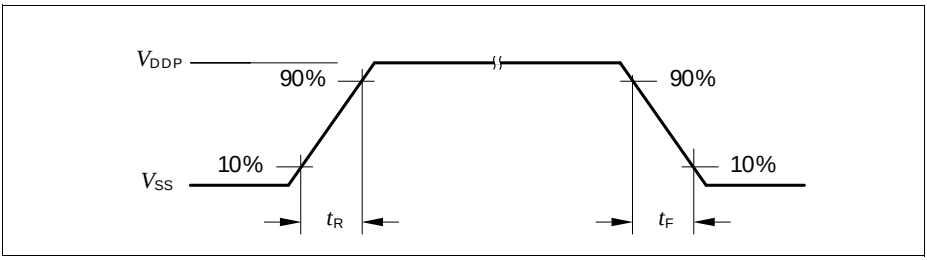


Figure 16 Rise/Fall Time Parameters

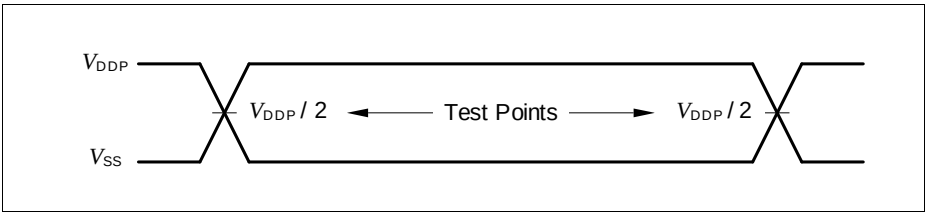


Figure 17 Testing Waveform, Output Delay

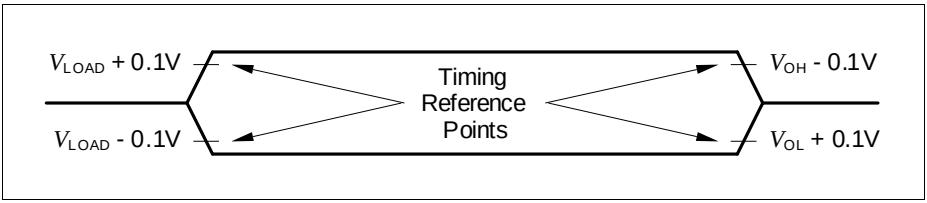


Figure 18 Testing Waveform, Output High Impedance

Figure 20 shows the typical curves for the accuracy of DCO1, with and without calibration based on temperature sensor, respectively.

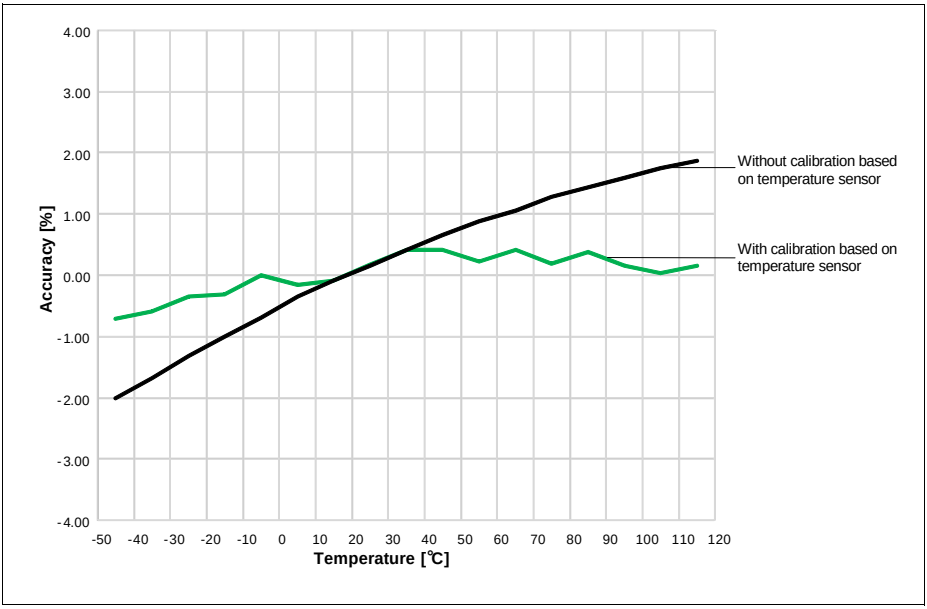


Figure 20 Typical DCO1 accuracy over temperature

Table 26 provides the characteristics of the 32 kHz clock output from digital controlled oscillators, DCO2 in XMC1300.

Table 26 32 kHz DCO2 Characteristics (Operating Conditions apply)

Parameter	Symbol		Limit Values			Unit	Test Conditions
			Min.	Typ.	Max.		
Nominal frequency	f_{NOM}	CC	–	32.75	–	kHz	under nominal conditions[1] after trimming
Accuracy	Δf_{LT}	CC	-1.7	–	3.4	%	with respect to f_{NOM}(typ), over temperature (0 °C to 85 °C)
			-3.9	–	4.0	%	with respect to f_{NOM}(typ), over temperature (-40 °C to 105 °C)

1) The deviation is relative to the factory trimmed frequency at nominal V_{DDC} and T_A = + 25 °C.

3.3.5 SPD Timing Requirements

The optimum SPD decision time between 0_B and 1_B is 0.75 µs. With this value the system has maximum robustness against frequency deviations of the sampling clock on tool and on device side. However it is not always possible to exactly match this value with the given constraints for the sample clock. For instance for a oversampling rate of 4, the sample clock will be 8 MHz and in this case the closest possible effective decision time is 5.5 clock cycles (0.69 µs).

Table 28 Optimum Number of Sample Clocks for SPD

Sample Freq.	Sampling Factor	Sample Clocks 0_B	Sample Clocks 1_B	Effective Decision Time[1)]	Remark
8 MHz	4	1 to 5	6 to 12	0.69 µs	The other closest option (0.81 µs) for the effective decision time is less robust.

1) Nominal sample frequency period multiplied with 0.5 + (max. number of 0_B sample clocks)

For a balanced distribution of the timing robustness of SPD between tool and device, the timing requirements for the tool are:

- Frequency deviation of the sample clock is +/- 5%
- Effective decision time is between 0.69 µs and 0.75 µs (calculated with nominal sample frequency)

3.3.6.2 Inter-IC (IIC) Interface Timing

The following parameters are applicable for a USIC channel operated in IIC mode.

Note: Operating Conditions apply.

Table 31 USIC IIC Standard Mode Timing[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Fall time of both SDA and SCL	t_1 CC/SR	-	-	300	ns	
Rise time of both SDA and SCL	t_2 CC/SR	-	-	1000	ns	
Data hold time	t_3 CC/SR	0	-	-	µs	
Data set-up time	t_4 CC/SR	250	-	-	ns	
LOW period of SCL clock	t_5 CC/SR	4.7	-	-	µs	
HIGH period of SCL clock	t_6 CC/SR	4.0	-	-	µs	
Hold time for (repeated) START condition	t_7 CC/SR	4.0	-	-	µs	
Set-up time for repeated START condition	t_8 CC/SR	4.7	-	-	µs	
Set-up time for STOP condition	t_9 CC/SR	4.0	-	-	µs	
Bus free time between a STOP and START condition	t_{10} CC/SR	4.7	-	-	µs	
Capacitive load for each bus line	C_b SR	-	-	400	pF	

1) Due to the wired-AND configuration of an IIC bus system, the port drivers of the SCL and SDA signal lines need to operate in open-drain mode. The high level on these lines must be held by an external pull-up device, approximalely 10 kOhm for operation at 100 kbit/s, approximately 2 kOhm for operation at 400 kbit/s.

4.2 Package Outlines

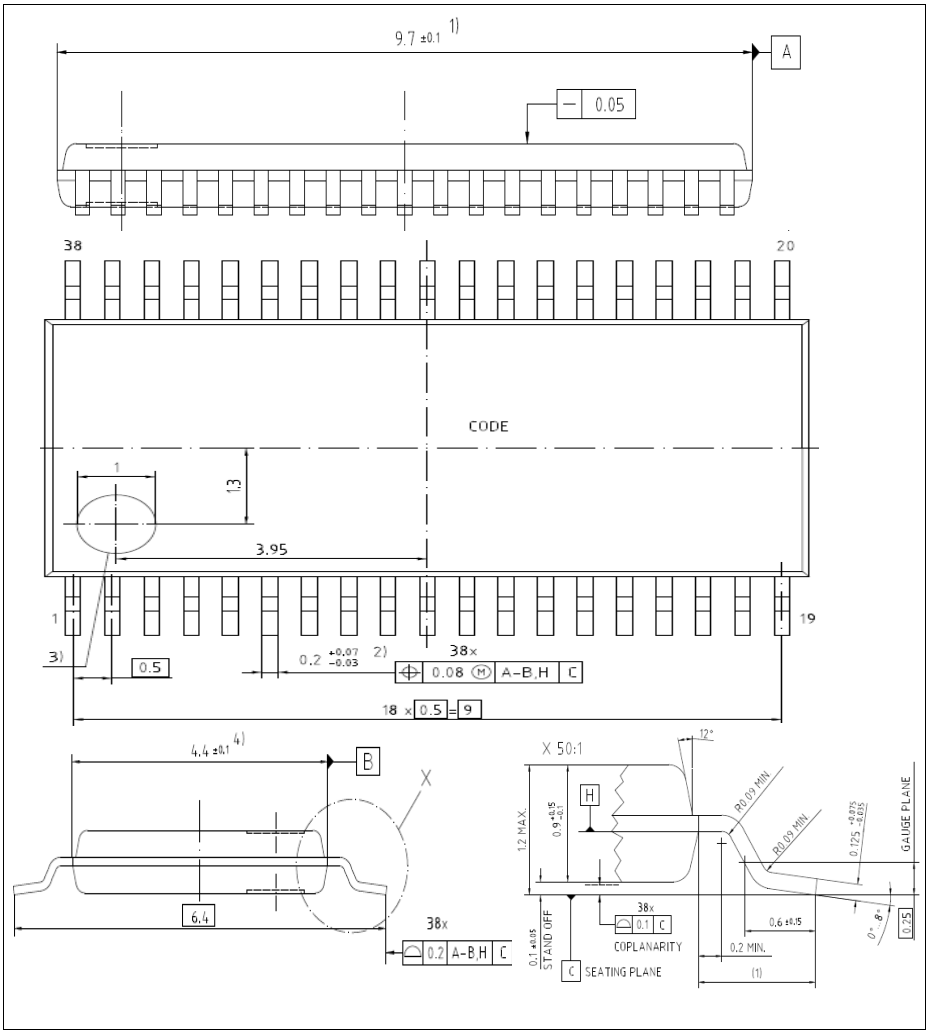


Figure 26 PG-TSSOP-38-9

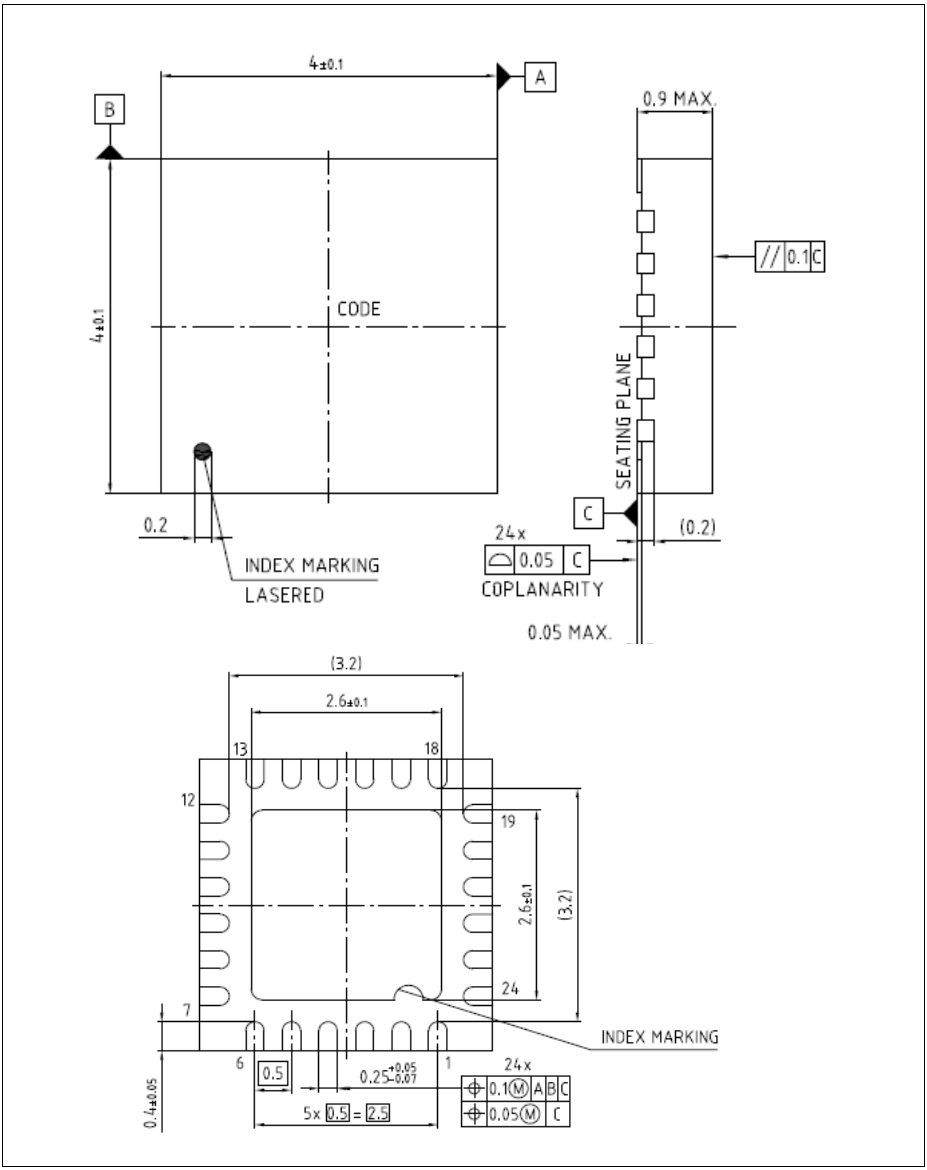


Figure 29 PG-VQFN-24-19

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